FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office			Docket No.: INTEL1520 (P18521)			Serial No.: 10/814,982				
					Applicants: Dublin, et al.					
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Date: rch 30, 2004		Grou 17	ıp Art Uni 44	t:	
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/Unsu Jung/				04/19/2007						

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PADENIA Complete if Known Substitute for form 1449/PTO 10/814,982 Application Number Filing Date March 30, 2004 INFORMATION DISCLOSURE First Named Inventor Valery M. DUBIN STATEMENT BY APPLICANT 1641 Art Unit (Use as many sheets as necessary) Examiner Name U. Jung 070702009500 Sheet of Attomey Docket Number

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